



## **INFORMATION DISCLOSURE CITATION**

(Use several sheets if necessary)

AUG 20 2004

**Docket Number (Optional)**  
**BUR920030168 (17124)**

**Application Number**

10/707071

**Applicant(s)**

Darren L. Anand, et al.

**Filing Date**

Group Art Unit

## U.S. PATENT DOCUMENTS

## FOREIGN PATENT DOCUMENTS

**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)**

JK International Test Conference, 1998 Proceedings, "Semiconductor Manufacturing Process Monitoring using Built-In Self-Test for Embedded Memories", Ivo Schanstra, Dharmajaya Lukita, Ad J. van de Goor, Kees Veelenturf, Paul J. van Winnen, pp. 872-881

<b>EXAMINER</b>	/James Kerveros/	<b>DATE CONSIDERED</b>	03/20/2007
-----------------	------------------	------------------------	------------

**EXAMINER:** Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

11/19/2003

## ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18

Stylesheet Version v18.0

Title of  
Invention

AUTOMATIC BIT FAIL MAPPING FOR EMBEDDED  
MEMORIES WITH CLOCK MULTIPLIERS

Application Number :

10/707,071

Confirmation Number:

First Named Applicant: Darren Anand

Attorney Docket Number: BUR920030168US1

Art Unit:

2138

Examiner:

JAMES C. KERVEROS

Search string:

( 4876685 or 5936876 or 6185709 or 6509766 or 0084387 ).pn

### US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
IJK/	1	4876685	1989-10-24	Rich			
	2	5936876	1999-08-10	Sugasawara			
	3	6185709	2001-02-06	Dreibelbis et al			
	4	6509766	2003-01-21	Pomichter et al			
V	5	0084387	2003-05-01	Rooney et al			

### Signature

Examiner Name	Date
/James Kerveros/	03/20/2007